

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

**INFORMATION DISCLOSURE  
STATEMENT**

Docket Number:  
**10456/28**

Application Number  
**To be assigned**

Filing Date  
**Herewith**

Examiner  
**To be assigned**

Art Unit  
**To be assigned**

Invention Title  
**IMAGE CLASSIFICATION**

Applicant(s)  
**Jon Christopher WILLIS**

Address to:  
Mail Stop PCT  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

1. In accordance with the duty of disclosure under 37 C.F.R. § 1.56 and in conformance with the procedures of 37 C.F.R. §§ 1.97 and 1.98 and M.P.E.P. § 609, attorneys for Applicant(s) hereby brings the following references to the attention of the Examiner. The references are listed on the attached modified PTO Form No. 1449. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.
2. A copy of the patents listed on the modified PTO form 1449 are enclosed, unless otherwise indicated.

Dated: 9/14/2006

By: Gerard A. Messina, Reg. No. 35,952

KENYON & KENYON LLP  
One Broadway  
New York, New York 10004  
(212) 425-7200 (telephone)  
(212) 425-5288 (facsimile)

Customer No. 26646

EV 839711839 US

<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT PTO-1449</b>	DOCKET NO. <b>10456/28</b>	SERIAL NO. <b>10/593019</b> To be assigned
	APPLICANT <b>Jon Christopher WILLIS</b>	
	FILING DATE Herewith	GROUP To be assigned

## U. S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT/PUBLICATION NUMBER	PATENT/PUBLICATION DATE	NAME	CLA SS	SUBCLASS	FILING DATE

## FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						Yes	No

## OTHER DOCUMENTS

EXAMINER INITIAL		AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.
		WILLIS C.J.: "Hyperspectral image classification with limited training data samples using feature subspaces" PROCEEDINGS OF THE SPIE – THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING SPIE-INT. SOC. OPT. ENG USA, vol. 5425, no. 1, 2004, pages 170-181, XP002330102, ISSN: 0277-786X, the whole document.*
		ALKOOT F M ET AL: "Multiple expert system design by combined feature selection and probability level fusion" INFORMATION FUSION, 2000. FUSION 2000. PROCEEDINGS OF THE THIRD INTERNATIONAL CONFERENCE ON JULY 19013, 2000, PISCATAWAY, NJ, USA, IEEE, vol. 2, 10 July 2000 (2000-07-10), pages 9-15, XP010505138, ISBN: 2-7257-0000-0, page 9 – page 10.*
		WILLIS C J: "Classification of hyperspectral imagery using limited training data samples" PROCEEDINGS OF THE SPIE-THE INTERNATIONAL SOCIETY FOR OPTICAL ENGINEERING SPIE-INT. SOC. OPT. ENG USA, vol. 4885, 2003, pages 379-388, XP002330102, ISSN: 0277-786X, cited in the application, the whole document.*
		JAIN A K ET AL: "STATISTICAL PATTERN RECOGNITION: A REVIEW" IEEE TRANSACTIONS ON PATTERN ANALYSIS AND MACHINE INTELLIGENCE, IEEE INC. NEW YORK, US, vol. 22, no. 1, January 2000 (2000-01), pages 4-37, XP000936788, ISSN: 0162-8828, page 11, left-hand column, line 2 - page 17, left-hand column, line 4, tables 4, 5, 7.*
		HO T K: "THE RANDOM SUBSPACE METHOD FOR CONSTRUCTING DECISION FORESTS" IEEE TRANSACTIONS ON PATTERN ANALYSIS AND MACHINE INTELLIGENCE, IEEE INC. NEW YORK, US, vol. 20, no. 8, August 1998 (1998-08), pages 832-844, XP000774454, ISSN: 0162-8828, abstract, page 833, right-hand column, line 2 – page 834, left-hand column, line 4.*

\* Copy of reference is not enclosed because reference is cited and described in Search Report (copy of reference provided by the International Searching Authority).

EXAMINER	DATE CONSIDERED
EXAMINER: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	